# MSKSEMI 美森科













**ESD** 

TVS

TSS

MOV

GDT

PIFD

# **WPM2015-MS**

Product specification





### **Features**

TrenchFET Power MOSFET

## **APPLICATION**

- Load Switch for Portable Devices
- DC/DC Converter

# P-Channel 20-V(D-S) MOSFET

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	l <sub>D</sub>
201/	90 mΩ@-4.5V	
-20 V	110 mΩ@-2.5V	-3 A

## **Reference News**

PACKAGE	OUTLINE	PIN Configuration	Marking
SOT-	1. GATE 2. SOURCE 3. DRAIN	G S	AFCP <del>©</del> ·

# Maximum ratings (T₂=25℃ unless otherwise noted)

Parameter	Symbol	Value	Unit	
Drain-Source Voltage	V <sub>DS</sub>	-20	V	
Gate-Source Voltage	V <sub>G</sub> s	±8		
Continuous Drain Current	l <sub>D</sub>	-3		
Pulsed Drain Current	Ірм	-10	A	
Continuous Source-Drain Diode Current	ls	-0.72		
Maximum Power Dissipation	P <sub>D</sub>	0.4	W	
Thermal Resistance from Junction to Ambient(t ≤5s)	RθJA	312.5	°C/W	
Junction Temperature	TJ	150		
Storage Temperature	T <sub>stg</sub>	-55 ~+150	℃	



# $T_a$ =25 $^{\circ}$ C unless otherwise specified

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Static						
Drain-source breakdown voltage	V(BR)DSS	$V_{(BR)DSS}$ $V_{GS} = 0V$ , $I_D = -250\mu A$ -20				
Gate-source threshold voltage	V <sub>G</sub> S(th)	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250µA	-0.4		-1	V
Gate-source leakage	Igss	V <sub>DS</sub> =0V, V <sub>GS</sub> =±8V			±100	nA
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =-20V, V <sub>GS</sub> =0V			-1	μA
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-2.8A		0.080	0.90	
Drain-source on-state resistance <sup>a</sup>	RDS(on)	V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2.0A		0.90	0.110	Ω
Forward transconductance <sup>a</sup>	<b>g</b> fs	Vps =-5V, Ip =-2.8A		6.5		S
Dynamic <sup>b</sup>						
Input capacitance	C <sub>iss</sub>			405		
Output capacitance	Coss	C <sub>oss</sub> V <sub>DS</sub> =-10V,V <sub>GS</sub> =0V,f =1MHz		75		
Reverse transfer capacitance	C <sub>rss</sub>			55		pF
		V <sub>DS</sub> =-10V,V <sub>GS</sub> =-4.5V,I <sub>D</sub> =-3A		5.5	10	
Total gate charge	Qg	Qg		3.3	6	
Gate-source charge	Q <sub>gs</sub>	Q <sub>gs</sub>		0.7		nC
Gate-drain charge	Q <sub>gd</sub>	V <sub>DS</sub> =-10V,V <sub>GS</sub> =-2.5V,I <sub>D</sub> =-3A		1.3		
Gate resistance	Rg	f=1MHz		6.0		Ω
Turn-on delay time	td(on)			11	20	
Rise time	tr	V <sub>DD</sub> =-10V,		35	60	
Turn-off delay time	t <sub>d(off)</sub>	R <sub>L</sub> =10Ω, I <sub>D</sub> =-1A,		30	50	ns
Fall time	tf	$V_{GEN}$ =-4.5 $V$ , $Rg$ =1 $\Omega$		10	20	
Drain-source body diode ch	aracteristic	s			•	
Continuous source-drain diode current	ls	T <sub>C</sub> =25℃			-1.3	
Pulse diode forward current <sup>a</sup>	I <sub>SM</sub>				-10	Α
Body diode voltage	V <sub>SD</sub>	Is=-0.7A		-0.8	-1.2	V

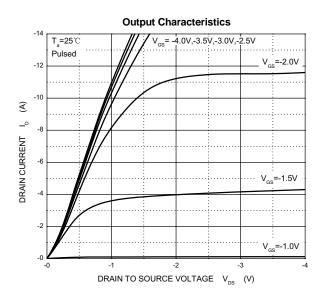
#### Notes:

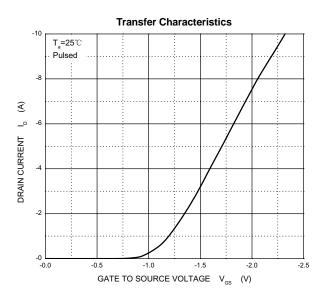
a.Pulse Test : Pulse Width < 300µs, Duty Cycle ≤2%.

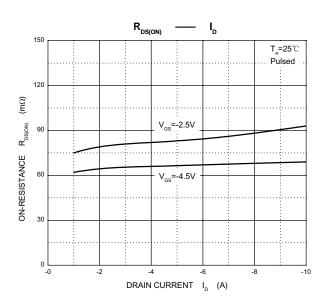
b.Guaranteed by design, not subject to production testing.

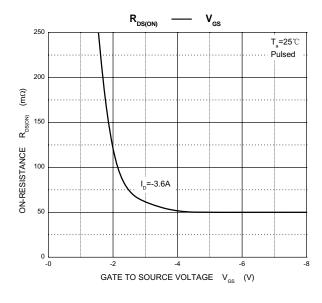


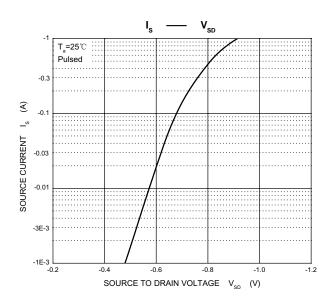
# **Typical Characteristics**





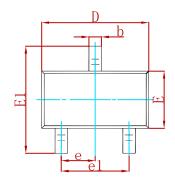


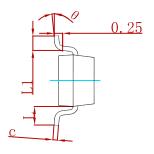


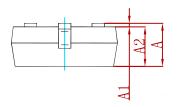




## PACKAGE MECHANICAL DATA

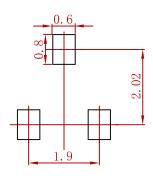






Symbol	Dimensions In Millimeters		Dimensions In Inches	
Symbol	Min	Max	Min	Max
А	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

# **Suugested Pad Layout**



#### Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

## **REELSPECIFICATION**

P/N	PKG	QTY
WPM2015-MS	SOT-23-3	3000



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